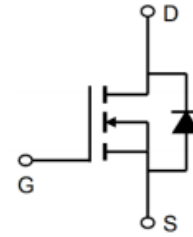


## Description

The GR2K2R30 is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.



## General Features

$V_{DS} = 300V$   $I_D = 3A$

$R_{DS(ON)} < 4000m\Omega$  @  $V_{GS} = 10V$  (Type: 2600m $\Omega$ )

## Application

Load switch  
Uninterruptible power supply



## Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
GR2K2R30	TO-92-3L	GR2K2R30 XXX YYYY	4000

## Absolute Maximum Ratings ( $T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	300	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	3	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	1.7	A
IDM	Pulsed Drain Current <sup>2</sup>	9	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation <sup>3</sup>	1.5	W
TSTG	Storage Temperature Range	-55 to 150	°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θJA</sub>	Thermal Resistance Junction-ambient <sup>1</sup>	100	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>	30	°C/W

**Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	300	330	--	V
VGS(th)	Gate-Source Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.0	3.5	4.0	V
RDS(on)	Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.5A	--	2600	4000	mΩ
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 300V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 25°C	--	--	1	μA
		V <sub>DS</sub> = 240V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C	--	--	100	
IGSS	Gate-Source Leakage	V <sub>GS</sub> = ±20V	--	--	±100	nA
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 20V, f = 1.0MHz	--	138	--	pF
C <sub>oss</sub>	Output Capacitance		--	30	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	5	--	
Q <sub>g</sub>	Total Gate Charge	V <sub>DD</sub> = 240V, I <sub>D</sub> = 3.0A, V <sub>GS</sub> = 10V	--	4.4	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	0.7	--	
Q <sub>gd</sub>	Gate-Drain Charge		--	2	--	
td(on)	Turn-on Delay Time	V <sub>DD</sub> = 150V, I <sub>D</sub> = 3.0A, R <sub>G</sub> = 25 Ω	--	18	--	ns
t <sub>r</sub>	Turn-on Rise Time		--	55	--	
td(off)	Turn-off Delay Time		--	60	--	
t <sub>f</sub>	Turn-off Fall Time		--	55	--	
I <sub>S</sub>	Continuous Body Diode Current	T <sub>C</sub> = 25 °C	--	--	3	A
ISM	Pulsed Diode Forward Current		--	--	12	
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 3A, di <sub>F</sub> /dt = 100A/μs	--	250	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	1.8	--	μC
V <sub>SD</sub>	Body Diode Voltage	T <sub>J</sub> = 25°C, I <sub>SD</sub> = 3A, V <sub>GS</sub> = 0V	--	--	1.4	V

**Note :**

- 1、 The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The power dissipation is limited by 150°C junction temperature
- 4、 The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

## Typical Characteristics

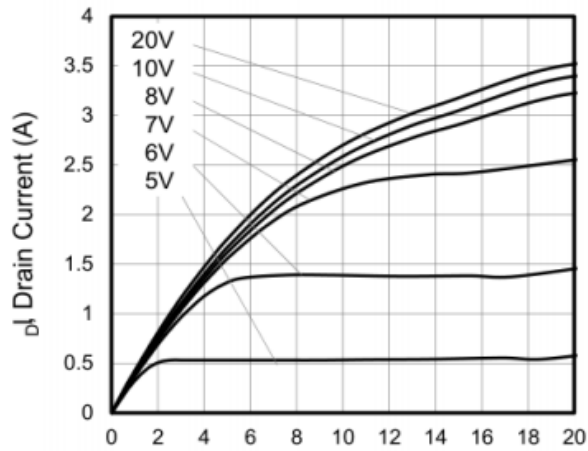


Figure 1. Output Characteristics

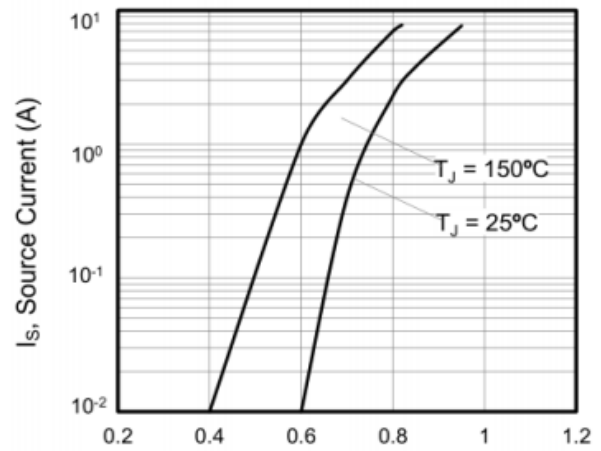
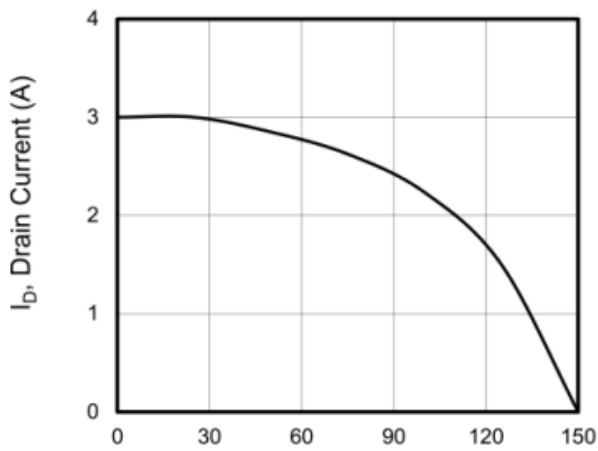
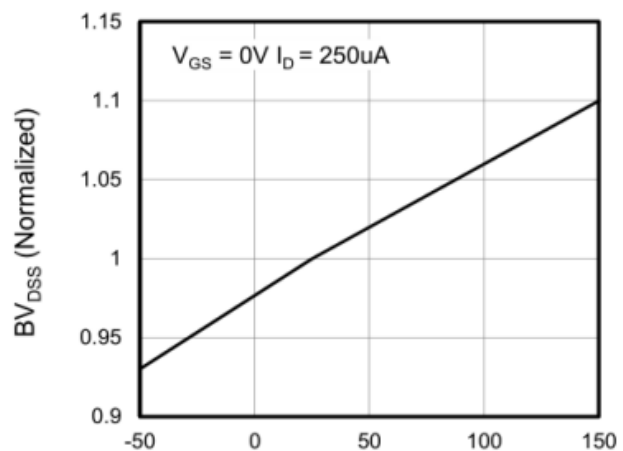


Figure 2. Body Diode Forward Voltage



T<sub>C</sub>, Case Temperature (°C)  
Figure 3. Drain Current vs. Temperature



T<sub>J</sub>, Junction Temperature (°C)  
Figure 4. BVDSS Variation vs. Temperature

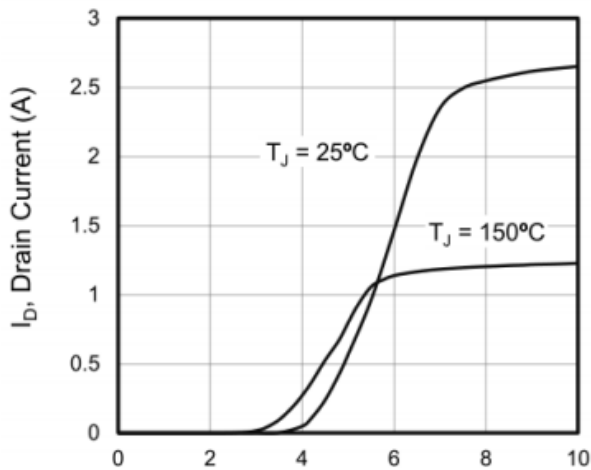


Figure 5. Transfer Characteristics

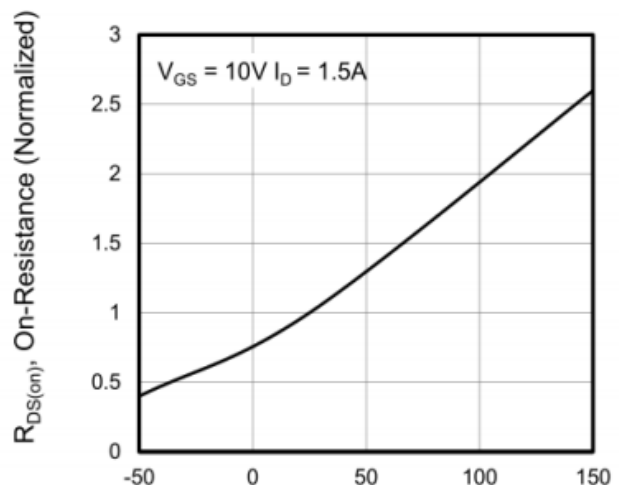


Figure 6. On-Resistance vs. Temperature

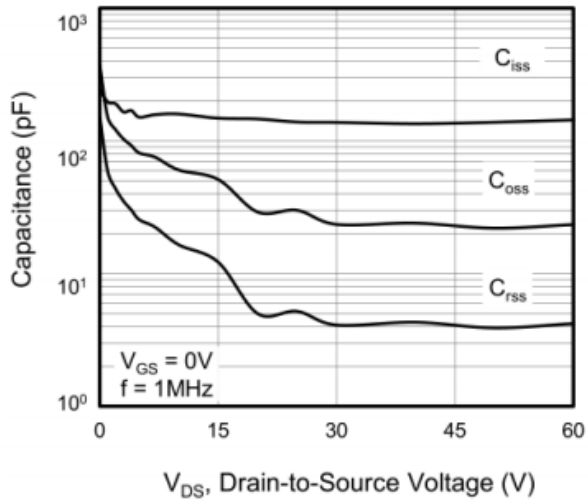


Figure 7. Capacitance

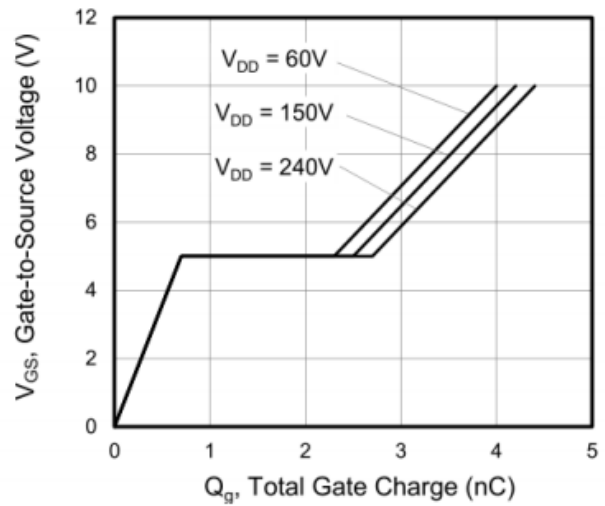


Figure 8. Gate Charge

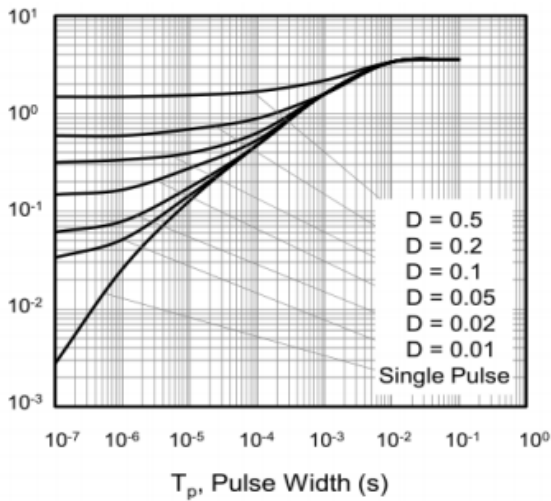
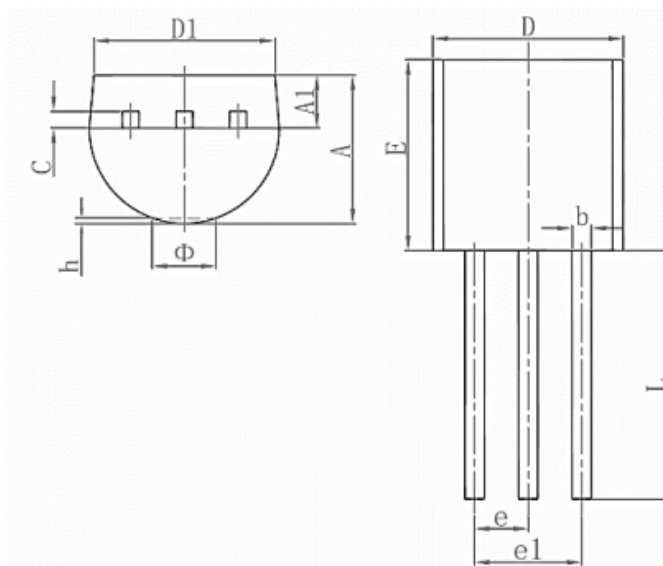


Figure 9. Transient Thermal Impedance

## Package Mechanical Data-TO-92-3LSingle



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	3.300	3.700	0.130	0.146
A1	1.100	1.400	0.043	0.055
b	0.380	0.550	0.015	0.022
c	0.360	0.510	0.014	0.020
D	4.400	4.700	0.173	0.185
D1	3.430		0.135	
E	4.300	4.700	0.169	0.185
e	1.270 TYP		0.050 TYP	
e1	2.440	2.640	0.096	0.104
L	14.100	14.500	0.555	0.571
Φ		1.600		0.063
h	0.000	0.380	0.000	0.015

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